

Name	Part #	Usage	Remarks
Portable SEM	TM3030plus	Surface observation	Magnification : 50 to 25000 times. Three-dimensional image can be obtained by deeper focus.
Energy Dispersion type X ray analyzer	Quantax70	Alien substance Element Analysis	Light Element more than Boron(B) can be detected. Point, Line and Mapping analysis is available.
Semiconductor device analyzer	B1500A	Electrical Performance Analysis	I-V, C-V and Wafer PCM measurement.
Manual Prober	MX-1000B	High / Low Temp. Probing	8 inch wafer available. Equipped with -40 to 200 degree C thermo-chuck.